Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/644,065	TAKAE ET AL.	
Examiner	Art Unit	
David Q. Nguyen	2617	

SEARCHED				
Class	Subclass	Date	Examiner	
455	558	9/14/2006	DN	
455	406	9/14/2006	DN	
455	407	9/14/2006	DN	
455	410	9/14/2006	DN	
455	411	9/14/2006	DN	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			-
interferer	t search-see nce search ntout	9/14/2006	DN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East- see search printout	9/14/2006	DN
East-see interference search printout	9/14/2006	DN